



Line of Business

Semiconductor Industry

Established

1993

Leading Executive

Mr. Gabi Seligsohn
President & CEO

Nova Measuring Instruments Ltd.

Nova Measuring Instruments Ltd. is a leading global semiconductor equipment manufacturer with solutions and services that are used by 21 of the largest 25 IC manufacturers. Nova's expertise in Thin Film and Optical CD & shape profiling metrology systems are addressing the complex measurement and process control challenges of High Volume Production (HVM) in 300 & 200 mm IC manufacturing, from 90nm to the demanding 32nm and 22nm technology nodes.



Company Facts

- Pioneer and leader of Integrated Metrology
- Largest market share in Integrated Metrology
- Intellectual property: over 50 patents to date of all core technologies

Nova's Product Offering

Nova offers Integrated Metrology (IM) and Stand-alone (SA) metrology product lines addressing different metrology needs. These hardware products are complemented by advanced structure modeling and application development software empowering fab engineers with the automation and flexibility necessary to develop in-fab 2D/3D and in-die applications for high-end semiconductor devices.

Nova i500™ Next Generation Integrated Metrology

The Nova i500 is the next generation Integrated Metrology platform targeted at advanced technology nodes of 22nm and below in both CMP and Etch. With less than 1 second MAM time on measurement pad sizes as small as 25X25 microns, the throughput of the Nova i500 enables 100% pre & post polishing optical CD measurements.

Nova T500™ - Fastest OCD in the Market

NOVA T500 is a high throughput high accuracy stand-alone optical CD platform following the highly-successful 3090Next metrology tool. It addresses the toughest challenges the industry faces: increasing metrology sampling, improving metrology precision and reducing metrology cost of ownership (CoO).

- Fastest OCD in the market - 250 WPH 13 sites
- 30% more accurate
- 30% better tool-to-tool matching
- Small pad size
- Up to three metrology units for easy on-site upgrade path and extendibility to future metrology
- Wafer stress metrology option

NovaMARS™ - Optical CD Application Development Solution

Nova's state of the art metrology software features patented methods and proprietary algorithms suited for 1D, 2D and 3D metrology applications. NovaMARS™ is supported by cost-effective high-power computing solutions.

Nova MARS 4.0 provides a solution for semiconductor manufacturers developing advanced technology of 22nm and below who are faced with a need to visualize complex 3D structures by non-destructive and highly accurate metrology.

Service and Support

Nova is committed to long-term customer support and continuing innovation through its worldwide technical support network. This includes on-site technical staff, hot-line and web support, application support, spare parts centers, intensive training and documentation. In Q4 1999 the company has earned ISO 9002 registration.

NOVA®

partnering for process control

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